

**Notice of References Cited**

Application/Control No.

10/132,013

Applicant(s)/Patent Under

Reexamination  
NISHIWAKI ET AL.

Examiner

Anthony D Stashick

Art Unit

3728

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-4680876	07-1987	Peng	36/35 B
	B	US-3429545	02-1969	Michel	36/35 B
	C	US-5343639	09-1994	Kilgore et al.	36/29
	D	US-5607749	03-1997	Strumor	36/28
	E	US-4918838	04-1990	Chang	36/28
	F	US-5224278	07-1993	Jeon	36/29
	G	US-2001/0049888	12-2001	Krafsur et al.	36/28
	H	US-6487796	12-2002	Avar et al.	36/28
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

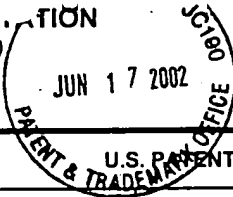
**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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## U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
<i>QJL</i>	A	D 392451	3/24/98	Collins et al.			
	B	D 405592	2/16/99	Strawser et al.			
	C	D 424289	5/9/00	Sorofman			
	D	D 432770	10/31/00	Breault			
	E	D 447852	9/18/2001	Schroeder			
	F	4120102	10/17/78	Kenigson			
	G	4217907	8/19/80	Meiller			
	H	4316335	2/23/82	Giese et al.			
	I	4521979	6/11/85	Blaser			
	J	4624062	11/25/86	Autry			
<i>QJL</i>	K	4845863	7/11/89	Yung-Mao			

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## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
<i>QJL</i>	L	55-47804	1980	Japan				✓
	M	61-021436	1/30/86	Japan			✓	
<i>QJL</i>	N	<del>62-194801</del>	<del>1987</del>	<del>Japan</del>				✓
	O	03170102	7/23/91	Japan			✓	
<i>QJL</i>	P	03-170104	7/23/91	Japan			✓	

## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

		Q	ASICS Spring 2002 Footwear Catalog, page1, published May 16, 2001

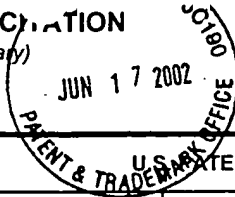
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## U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
<i>QPS</i>	R	5042175	7/11/89	Ronen et al			
	S	5044096	9/3/91	Polegato			
	T	5086574	2/11/92	Bacchiocchi			
	U	5092060	3/3/92	Frachey et al.			
	V	5172494	12/22/92	Davidson			
	W	5233767	8/10/93	Kramer			
	X	5343639	9/6/94	Kilgore et al.			
	Y	5369896	12/6/94	Frachey et al.			
	Z	5448839	9/12/95	Blissett et al.			
	AA	5611152	3/18/97	Richard et al			
<i>QPS</i>	AB	5625965	5/6/97	Blissett et al.			

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## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
<i>QPS</i>	AC	08-038211	2/13/96	Japan			✓	
<i>QPS</i>	AD	11-113605	4/27/99	Japan			✓	
<i>QPS</i>	AE	20001197503-A	7/18/00	Japan			✓	

## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)


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## U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
QAL	AF	5625965	5/6/97	Blissett et al.			
	AG	5782014	7/21/98	Peterson			
	AH	5832634	11/10/98	Wong			
	AI	5987781	11/23/99	Pavesi et al.			
	AJ	5992052	11/30/99	Moretti			
	AK	6007503	12/28/99	Berger et al.			
	AL	6035559	3/14/00	Freed et al.			
	AM	6041521	3/28/00	Wong			
	AN	6041522	3/28/00	Anteby			
	AO	6125557	10/3/00	Brown			
QAL	AP	6131310	10/17/00	Fang			

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## FOREIGN PATENT DOCUMENTS

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							YES	NO

## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)


EXAMINER

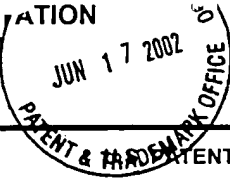
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## PATENT & TRADEMARK OFFICE PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
<i>CS</i>	AQ	6205684	3/27/01	Snyder			
	AR	6161315	12/19/00	Dalton			
	AS	6234987	5/22/2001	Chen			
	AT	6269555	8/7/01	Brown			
<i>CS</i>	Au	6282816	9/4/01	Rosendahl			

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## FOREIGN PATENT DOCUMENTS

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EXAMINER <i>Anthony Stark</i>	DATE CONSIDERED <i>9/24/03</i>
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